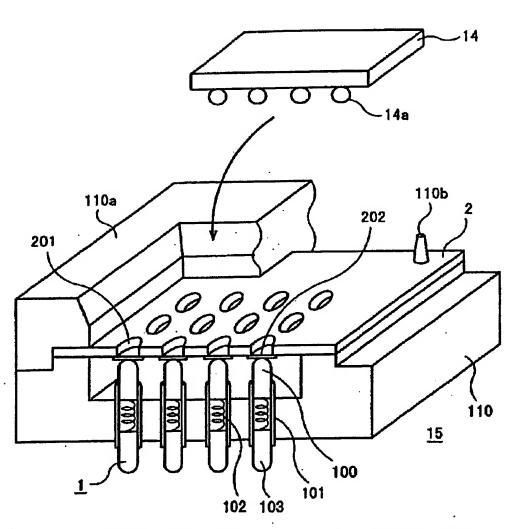
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 1 of 18

FIG.1



2: CONNECTING SHEET 110: SOCKET BASE

100: PLUNGER 110a: SOCKET LID

101: CYLINDER 110b: ALIGNING PIN

102: COIL SPRING 201: CONNECTING HOLE

103: TERMINAL PORTION 202: ELECTRODE PAD

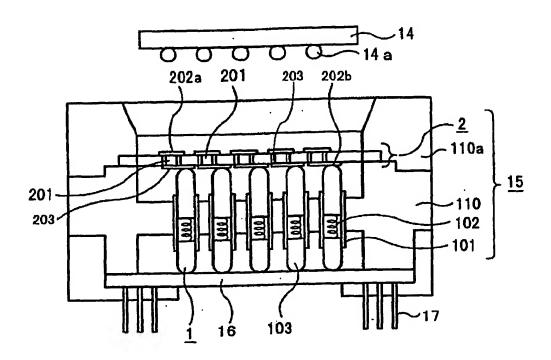
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 2 of 18

F I G. 2



202a, 202b: ELECTRODE PAD

203: CONNECTING WIRE

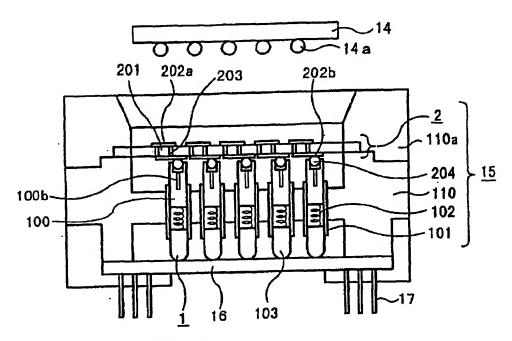
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 3 of 18

F I G. 3



100b: SLIT

204: PROJECTION-LIKE ELECTRODE

2.54

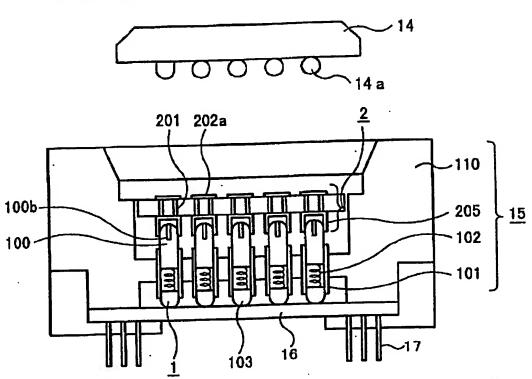
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 4 of 18

F 1 G. 4



100b: SLIT

205: RECESS-LIKE ELECTRODE

2.44

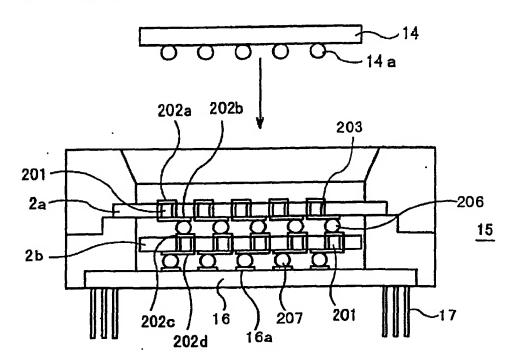
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 5 of 18

FIG.5



202a~d: ELECTRODE PAD

16a: ELECTRODE PAD

206: CONNECTING WIRE

207: CONNECTING TERMINAL

2

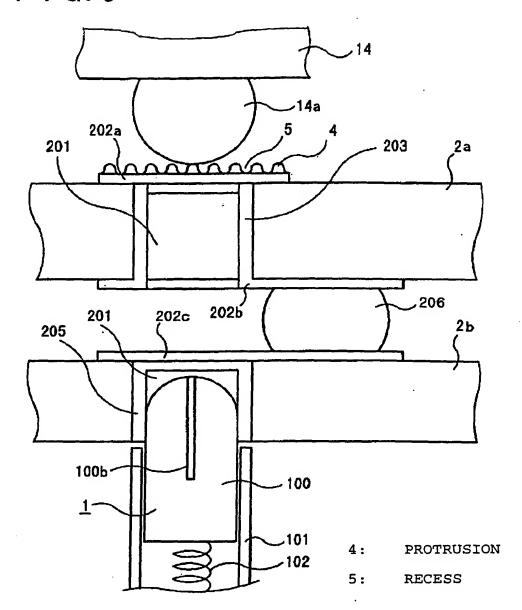
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 6 of 18

FIG.6



-

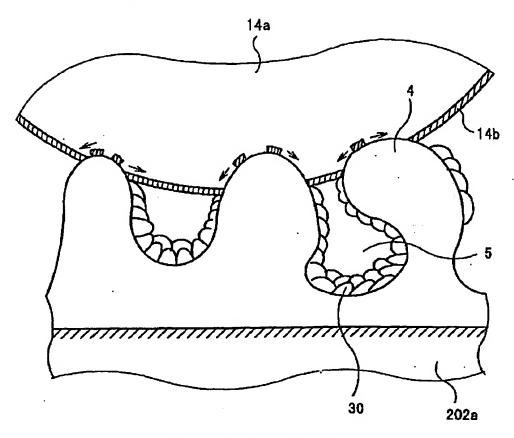
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 7 of 18

F | G.7



14b: OXIDE COATING

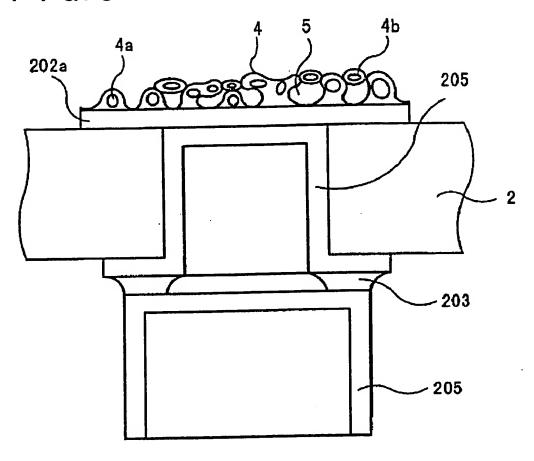
APPLN. FILING DATE: SEPTEMBER 11, 2003 **TITLE:** SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

SHEET 8 of 18 APPLICATION SERIAL NO: 028433-012

FIG.8



METALLIC PARTICLE 4a:

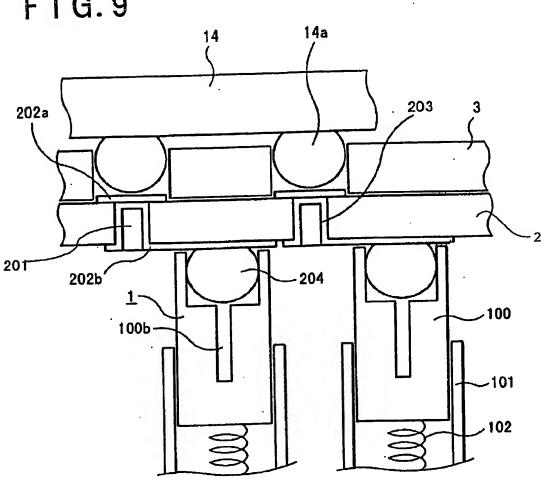
PLATING LAYER 4b:

TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

Inventor(s): Shigeki maekawa et al. Application Serial No: 028433-012 SHEET 9 of 18





GUIDING PLATE 3:

TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

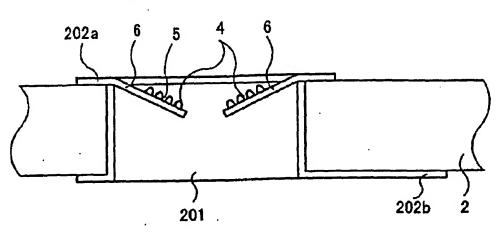
AND A CONNECTING SHEET USED FOR THE SAME

Inventor(s): Shigeki maekawa et al.

APPLICATION SERIAL NO: 028433-012 SHEET 10 of 18

F I G. 10

3 .44:



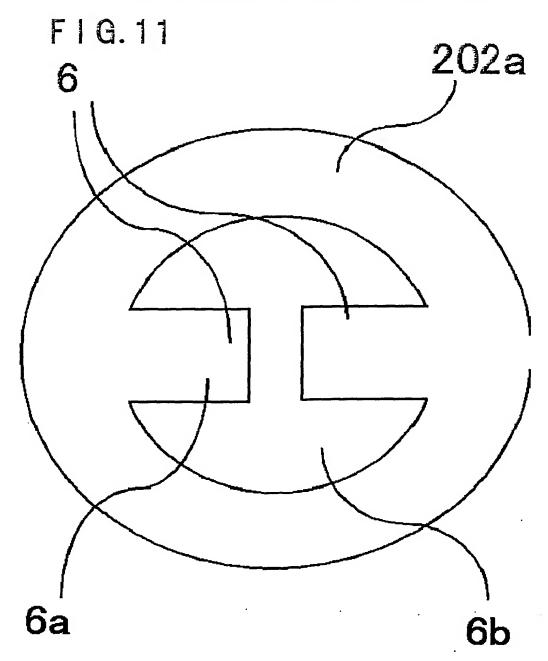
6: LEAD

TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 11 of 18



6: LEAD

6a: BENDING PORTION

6b: SPACED PORTION

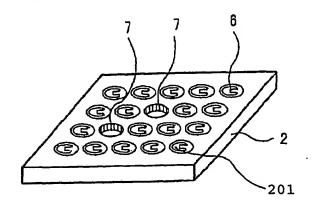
APPLN. FILING DATE: SEPTEMBER 11, 2003 **TITLE:** SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

SHEET 12 of 18 APPLICATION SERIAL NO: 028433-012

FIG. 12



7: THROUGH HOLE

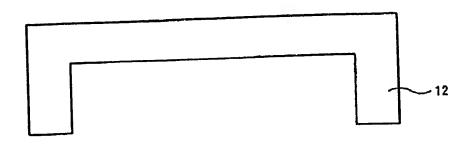
APPLN. FILING DATE: SEPTEMBER 11, 2003
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

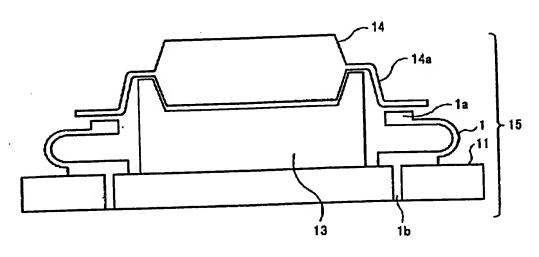
AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

SHEET 13 of 18. APPLICATION SERIAL NO: 028433-012

FIG. 13





1: PROBE

TIP PORTION 1a:

CONNECTING TERMINAL 1b:

HOUSING 11:

SECURING JIG 12:

SEAT 13:

SEMICONDUCTOR PACKAGE 14:

14a: OUTER CONNECTING TERMINAL

SOCKET 15:

TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 14 of 18

FIG. 14a

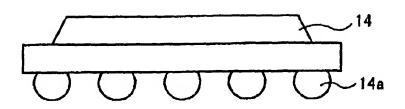
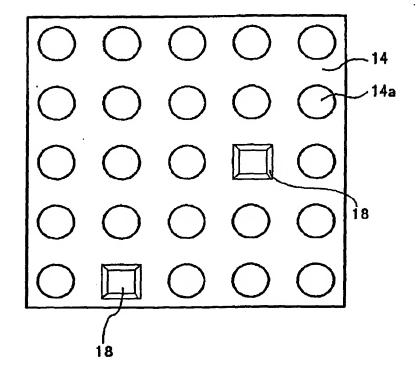


FIG. 14b



18: DIRECTION ALIGNING ELECTRODE

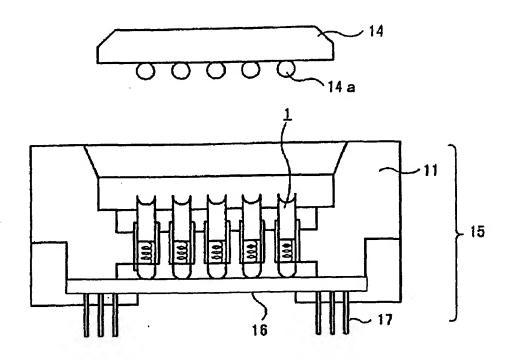
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 15 of 18

FIG. 15



16: CIRCUIT BOARD

17: CONNECTING PIN

2 -40

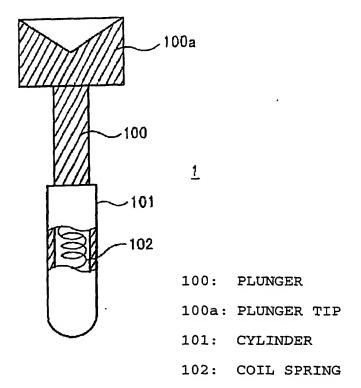
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 16 of 18

FIG. 16



3

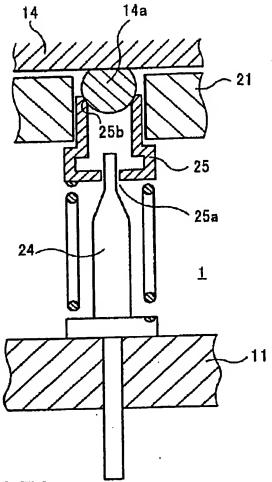
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

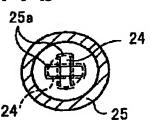
INVENTOR(S): SHIGEKI MAEKAWA ET AL.

APPLICATION SERIAL NO: 028433-012 SHEET 17 of 18

FIG. 17a



F I G. 17b



21: FLOATING PLATE

24: TWISTED LEAD PLATE

25: CONTACTING PART

25a: RECTANGULAR LEAD HOLE

25b: CONTACTING PART HAVING

TAPER-LIKE INNER PERIPHERY

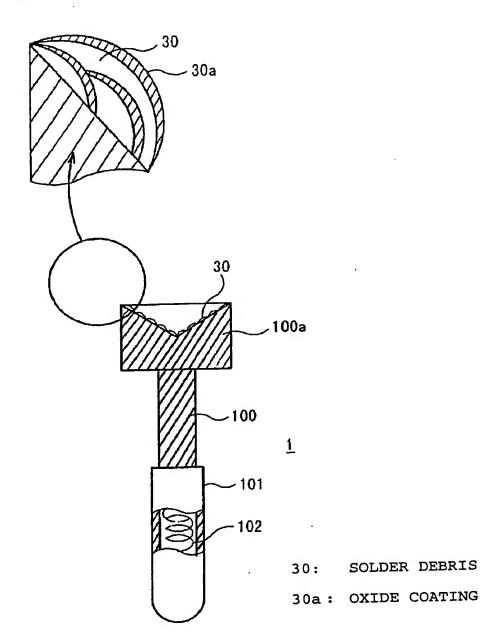
APPLN. FILING DATE: SEPTEMBER 11, 2003
TITLE: SOCKET FOR TESTING A SEMICONDUCTOR DEVICE

AND A CONNECTING SHEET USED FOR THE SAME

INVENTOR(S): SHIGEKI MAEKAWA ET AL.

SHEET 18 of 18 APPLICATION SERIAL NO: 028433-012

FIG. 18



3.364